

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

Product Affected: P78001 devices built in VFQFPN-56 Refer to Attachment II for the affected part numbers □ Pr □ Ba				
Refer to Attachment II for the affected part numbers Ba Da	ack Mark Lot# traceable to the actual test ate Code location ther			
Date Effective: 17-Jul-2015	. — —			
Contact: IDT PCN DESK Attact	hment: Yes No			
E-mail: pcndesk@idt.com Samp	Please contact your local sales representative for sample request.			
DESCRIPTION AND PURPOSE OF CHANGE:				
RELIABILITY/QUALIFICATION SUMMARY: Refer to correlation data shown in Attachment I.				
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory				
on the earlier version has been depleted.				
Customer:	pproval for shipments prior to effective date.			
Name/Date: E-Mail A	Address:			
Title: Phone#	Phone# /Fax# :			
CUSTOMER COMMENTS:				
IDT ACKNOWLEDGMENT OF RECEIPT:				
RECD. BY: DATE	E:			

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : A1504-02

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding Sigurd, Taiwan as the alternate Test facility. Present qualified test site is at IDT Penang, Malaysia.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Testers, load boards and test programs are compatible at the qualified facility. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the two test facilities with no change to the test coverage.

Electrical Test Correlation Results

Vehicle: P78001-500NDGI

Sample size: 200 electrically good units and 20 reject units

Description	Existing Test (IDT Penang, Malaysia)	Alternate Test (Sigurd, Taiwan)	
Tester Platform	Teradyne Flex	Teradyne Flex	
Loadboard & Test Program	IDT Load board and Test Program	IDT Load board and Test Program	
Test Site	Quad	Quad	
Test Temperature	Ambient (1st insert) 125°C (2nd insert)	Ambient (1st insert) 125°C (2nd insert)	
Test Correlation Results	100%	100%	
Number of Good Units Correlated @ ambient	200 pcs	200 pcs	
200 units Bin 1 handler run (good units)	Passed	Passed	
Number of Reject Units Correlated @ ambient	20 pcs	20 pcs	
20 units rejects handler run	Passed	Passed	
Number of Good Units Correlated @ hot	200 pcs	200 pcs	
200 units Bin 1 handler run (good units)	Passed	Passed	
Number of Reject Units Correlated @ hot	20 pcs	20 pcs	
20 units reject handler run	Passed	Passed	
200 units Bin 1 datalog correlation (good units)	Passed	Passed	
20 units rejects datalog correlation	Passed	Passed	

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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT II - PCN #: A1504-02

Affected Part Numbers

Part Number	Part Number	Part Number	Part Number
P78001-500NDGI	P78001-504NDGI	P78001-502NDGI8	P78001-501NDGI
P78001-505NDGI	P78001-503NDGI8	P78001-502NDGI	P78001-500NDGI8
P78001-504NDGI8	P78001-503NDGI	P78001-501NDGI8	P78001-505NDGI8